

TestForum 2014

Radisson Blu Hotel, Malmö, Sweden November 25th - 26th, 2014

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Test Forum 2014 Local Organizer

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Call for Papers / Presentations

The 2-day TestForum 2014, the 15th event in the series, is the major event for Test professionals in the Nordic area and the Baltic states. Every year the TestForum is attended by key people from the industry's test community as well as by international vendors of test and measurement equipment and solutions.

This year the event will take place in Radisson Blu Hotel, which is located in the center of Malmö.

Nordic Test Forum hereby cordially invites you to participate and submit your contribution to TestForum 2014, which includes (but is not limited to) the following topics:

- Functional Test
- Boundary Scan
- Embedded Instruments
- RF Testing
- AOI / AXI / SPI
- ICT / Flying Probe
- Test economics
- Power Test
- Fixturing/Interfaces
- Future technology trends and test challenges
- Best practices in manufacturing test
- ASIC: BIST / Mixed-signal / IDDQ / IDDT
- Board test SW, BIST, diagnostics
- Quality methods and tools
- Preventive test / Prognostics
- Design to Test transfer / Design for Test
- ESD
- Test efficiency and optimization
- Data acquisition / collection / analysis

Submissions

TestForum seeks full papers and/or presentations in the area of test of electronics, including *R&D*, *Application Contributions*, *Best Practices*, *Emerging Ideas*, etc. You are welcome to submit contributions also outside the above topics as long as they stay within the field of electronics test. Focus shall be on new and upcoming challenges, opportunities, techniques and best practices in electronics test technology rather than on particular products.

Proceedings

The accepted contributions of authors that wish to provide the corresponding materials will be delivered in electronic format at the Nordic Test Forum event.

The Format of the Event

- The event format will be a two-day workshop and a small exhibition attached to it.
- November 24th in the evening there is the AGM of the NTF.
- · The mix of presentations will decide the number of sessions.
- The presentations will be 30 minutes each: 25 minutes of speech and 5 minutes for questions and comments.
- Poster display of selected material a recommended option at the breaks after each session - will allow each presenter to obtain more focus on his/her presentation.
- In the exhibition, attendees will have a chance to see the latest equipment and talk to exhibitors.

Key Dates

- · Abstract submission:
- Notification of acceptance:
- Conference registration
- Presentation slides:

August 29, 2014 September 12, 2014 October 15, 2014 October 31, 2014

Further Information and Submissions

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Visit the NTF web pages at: http://www.nordictestforum.org







